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FORM PTO-1449					ATTY. DOCKET NO. APPLICATION NO. To Be Assigned					
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0	AR	1	Clark Lawrence T "A High-Voltage Output Buffer Fabricated on a 2V CMOS Technology,"							
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1	AR	2	Schroder, Dieter K., "Semiconductor Material and Device Characterization," Fig. 6.40, Charge-to breakdown as a function of oxide thickness, John Wiley & Sons, Inc., 2 nd Edition, p. 397, 1998.						
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